

**Search Notes**

Application/Control No.

10/792,293

Examiner

Patrick J. Lee

Applicant(s)/Patent under  
Reexamination

LOEW ET AL.

Art Unit

2878

**SEARCHED**

Class	Subclass	Date	Examiner
250	205, 208.1, 214C	12/12/05 2/14/05	PL
327	514	12/14/2005	PL
313	531	12/14/2005	PL
315	10	12/14/2005	PL
315	156-159	12/14/2005	PL
Updated	search	3/27/2006	PL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference Search Attached		4/10/2006	PL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	12/12/2005	PL
Consulted w/ S. Allen AU 2878 CL 250	12/13/2005	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	12/14/2005	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	3/27/2006	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	4/10/2006	PL